EAST Search History

10/608,798

Ref #	Hits	Search Query	DBs	Default Operator	Plurals	Time Stamp
L1	18	identify$3 and (type$1 near1 failure$1 with semiconductor device)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	ADJ	ON	2006/03/24 14:44
L2	17848	decision circuit$2	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	ADJ	ON	2006/03/24 14:45
L3	12	l1 and l2	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	ADJ	ON	2006/03/24 14:45
L4	3390	additional procedure	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	ADJ	ON	2006/03/24 14:46
L5	335515	repair	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	ADJ	ON	2006/03/24 14:46
L6	11129	additional test	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	ADJ	ON	2006/03/24 14:46
L7	236	determin$3 and ((failure$1 or error$1) with repairable)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	ADJ	ON	2006/03/24 14:47
L8	14	l5 and l6 and l7	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	ADJ	ON	2006/03/24 15:01

EAST Search History

L9	10	I8 and I4	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	ADJ	ON	2006/03/24 14:47
L10	10	I9 and I3	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	ADJ	ON	2006/03/24 14:51
L11	13756	714/724 or 714/746 or 714/704 or 714/753 or 714/? or 702/?	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	ADJ	ON	2006/03/24 15:06
L12	7	I11 and I8	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	ADJ	ON	2006/03/24 15:06